

# Empirical Processes

MAA110 - EPFL

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**Binary classification.** Consider an input r.v. valued in a measurable space  $\mathcal{X} \subset \mathbb{R}^d$ , with  $d \in \mathbb{N}^*$ , and an output r.v.  $Y$  valued in  $\{0, 1\}$ . Denote by  $P$  the joint distribution of  $(X, Y)$ , and define the regression function (posterior distribution) by

$$\eta : x \in \mathcal{X} \mapsto P(Y = 1|X = x) .$$

**Exercise 1.** Derive the explicit formula for  $\eta$  as function of  $\theta$  and  $p$ , when we consider first that  $\mathcal{X} \subset [0, 1]$ , and  $P$  such that:

1. the conditional distribution of  $X$  given  $Y = 0$  is  $P_0 = \mathcal{U}([0, \theta])$ , with  $\theta \in (0, 1)$
2. the conditional distribution of  $X$  given  $Y = 1$  is  $P_1 = \mathcal{U}([\theta, 1])$
3.  $p = \mathbb{P}(Y = 1) \in (0, 1)$ .

**Exercise 2** (Bayes classifier). Suppose now that  $\mathcal{X} \subset \mathbb{R}_+$ , and denote by  $P_X$  the marginal of  $X$ , as well as the regression function given by:

$$\eta : x \in \mathcal{X} \mapsto \frac{x}{x + \theta} ,$$

for all  $\theta > 0$ . Consider a collection of classifiers  $\mathcal{H} = \{h : \mathcal{X} \rightarrow \{0, 1\}, h \text{ measurable}\}$ . The associate binary loss is defined as

$$\ell_h : (x, y) \in \mathcal{X} \times \{0, 1\} \mapsto 1\{h(x) \neq y\} ,$$

i.e., equals to 1 if the predictor  $h$  mislabels the input  $x$ . The goal is to find the optimal classifier known as the *Bayes classifier*  $h^*$ , that minimizes the associated risk

$$\mathcal{R}(h) = \mathbb{E}[\ell_h(X, Y)] = \mathbb{P}(h(X) \neq Y) .$$

1. Recall the minimization problem for which  $\eta$  is the unique solution.
2. Derive the explicit formula for the risk as function of  $\eta$ .
3. Prove that the Bayes risk equals to

$$\mathcal{R}(h^*) = \int_{\mathcal{X}} \min(\eta(x), 1 - \eta(x)) dP_X(x)$$

Deduce the explicit formula for  $h^*$  as function of  $\eta$ .

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4. Derive the Bayes risk for  $P_X = \mathcal{U}([0, \alpha\theta])$ , with  $\alpha > 1$

**Exercise 3.** Consider the r.v.  $X = (T, U, V)$ , of independent coordinates distributed from a standard exponential distribution. Let  $\theta > 0$  be fixed and define the response variable by  $Y = 1\{T + U + V \leq \theta\}$ .

1. Derive the Bayes function when  $V$  is not observed, i.e.,  $h^*(T, U)$ , and the associated Bayes risk.
2. Consider now that  $T$  is not observed. Continue the above computations and compare the respective risk functions for  $\theta = 9$ .
3. Propose a classifier when none of the coordinates of  $X$  are observed. Derive its risk.

**Uniform convergence.** This exercise shows that if we are able to approximate (discretize) the function class  $\mathcal{H}$  into an (arbitrarily) finite class  $\mathcal{H}_\varepsilon$ , depending on  $\varepsilon$ , then we can prove a ULLN.

**Exercise 4** (Glivenko-Cantelli's Theorem with bracketing). Let  $(\Omega, \mathcal{A}, P)$  be a probability space. Consider a class  $\mathcal{H}$  of measurable functions  $h : \mathcal{X} \rightarrow \mathbb{R}$ , such that  $P|h| < \infty$ , and  $X$  a r.v. of probability distribution  $P$ . Let  $X_1, \dots, X_n$  an i.i.d. sample drawn from  $P$ , with  $n \in \mathbb{N}^*$ . Define the standard empirical process by

$$(h, \omega) \in \mathcal{H} \times \Omega \mapsto \frac{1}{\sqrt{n}} \sum_{i=1}^n (h(X_i) - \mathbb{E}h(X)) = \sqrt{n}(P_n(\omega) - P)(h) \in \mathbb{R} .$$

Let  $\varepsilon > 0$  be fixed. Suppose that there exists a class of functions  $\mathcal{H}_\varepsilon$  such that we can bound any function  $h \in \mathcal{H}$  by elements of  $\mathcal{H}_\varepsilon$ . Specifically, for all  $h \in \mathcal{H}$  we can find  $h_l, h_u \in \mathcal{H}_\varepsilon$ , such that  $h_l \leq h \leq h_u$ , and  $P(h_l - h_u) \leq \varepsilon$ .

Prove that

$$\|P_n - P\|_{\mathcal{H}} := \sup_{h \in \mathcal{H}} |P_n h - P h| \xrightarrow[n \rightarrow \infty]{a.s.} 0 .$$

**Exercise 5.** Prove that any continuous map between two metric spaces is Borel-measurable. Hint: Use the definition of measurable maps.